

TOSHIBA Photocoupler GaAs Ired &amp; Photo-Transistor

**TLP521-1, TLP521-2, TLP521-4**

Programmable Controllers

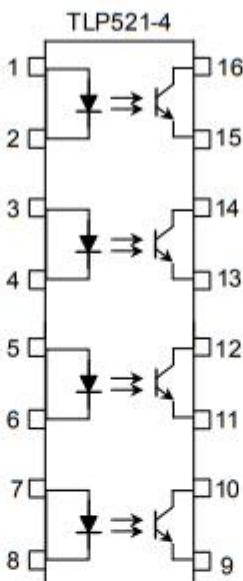
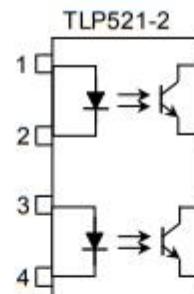
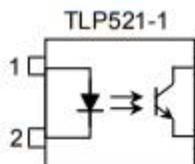
AC/DC-Input Module

Solid State Relay

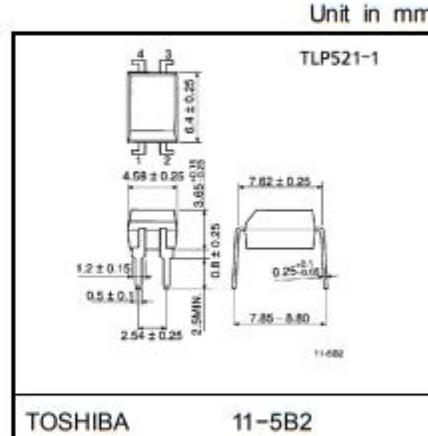
The TOSHIBA TLP521-1, -2 and -4 consist of a photo-transistor optically coupled to a gallium arsenide infrared emitting diode.

The TLP521-2 offers two isolated channels in an eight lead plastic DIP package, while the TLP521-4 provides four isolated channels in a sixteen lead plastic DIP package.

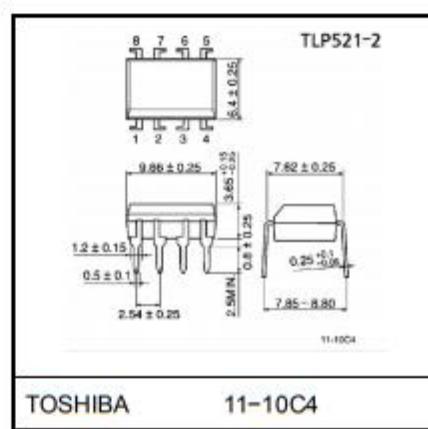
- Collector-emitter voltage: 55 V (min)
- Current transfer ratio: 50% (min)  
Rank GB: 100% (min)
- Isolation voltage: 2500 Vrms (min)
- UL recognized  
made in Japan: UL1577, file No. E67349  
made in Thailand: UL1577, file No. E152349

**Pin Configurations (top view)**

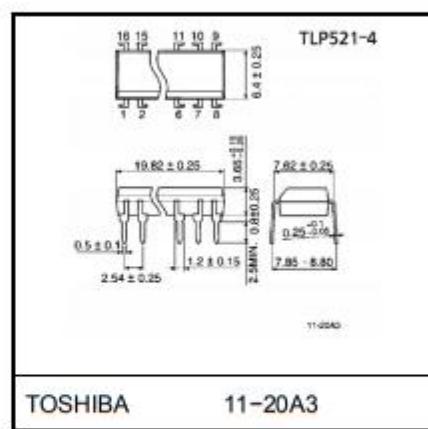
1 : Anode  
2 : Cathode  
3 : Emitter  
4 : Collector



Weight: 0.26 g



Weight: 0.54 g



Weight: 1.1 g

**Absolute Maximum Ratings (Ta = 25°C)**

Characteristic	Symbol	Rating		Unit
		TLP521-1	TLP521-2 TLP521-4	
LED	Forward current	I <sub>F</sub>	70	mA
	Forward current derating	ΔI <sub>F</sub> /°C	-0.93 (Ta ≥ 50°C)	mA /°C
	Pulse forward current	I <sub>FP</sub>	1 (100μ pulse, 100pps)	A
	Reverse voltage	V <sub>R</sub>	5	V
	Junction temperature	T <sub>j</sub>	125	°C
Detector	Collector-emitter voltage	V <sub>CEO</sub>	55	V
	Emitter-collector voltage	V <sub>ECO</sub>	7	V
	Collector current	I <sub>C</sub>	50	mA
	Collector power dissipation (1 circuit)	P <sub>C</sub>	150	mW
	Collector power dissipation derating (1 circuit Ta ≥ 25°C)	ΔP <sub>C</sub> /°C	-1.5	mW /°C
	Junction temperature	T <sub>j</sub>	125	°C
Storage temperature range	T <sub>stg</sub>	-55~125		°C
Operating temperature range	T <sub>opr</sub>	-55~100		°C
Lead soldering temperature	T <sub>sol</sub>	260 (10 s)		°C
Total package power dissipation	P <sub>T</sub>	250	150	mW
Total package power dissipation derating (Ta ≥ 25°C)	ΔP <sub>T</sub> /°C	-2.5	-1.5	mW /°C
Isolation voltage	BVs	2500 (AC, 1min., R.H.≤ 60%) (Note 1)		Vrms

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc.).

Note 1: Device considered a two terminal device: LED side pins shorted together and detector side pins shorted together.

**Recommended Operating Conditions**

Characteristic	Symbol	Min	Typ.	Max	Unit
Supply voltage	V <sub>CC</sub>	—	5	24	V
Forward current	I <sub>F</sub>	—	16	25	mA
Collector current	I <sub>C</sub>	—	1	10	mA
Operating temperature	T <sub>opr</sub>	-25	—	85	°C

Note: Recommended operating conditions are given as a design guideline to obtain expected performance of the device. Additionally, each item is an independent guideline respectively. In developing designs using this product, please confirm specified characteristics shown in this document.

Type	Classi- fication (*1)	Current Transfer Ratio (%) ( $I_C / I_F$ )		Marking Of Classification
		Min	Max	
TLP521	A	50	600	Blank, Y, Y*, G, G*, B, B*, GB
	Rank Y	50	150	Y, Y*
	Rank GR	100	300	G, G*
	Rank BL	200	600	B, B*
	Rank GB	100	600	G, G*, B, B*, GB
TLP521-2	A	50	600	Blank, GR, BL, GB
TLP521-4	Rank GB	100	600	GR, BL, GB

\*1: Ex. rank GB: TLP521-1 (GB)

(Note): Application type name for certification test, please use standard product type name, i.e.

TLP521-1 (GB): TLP521-1, TLP521-2 (GB): TLP521-2

**Individual Electrical Characteristics (Ta = 25°C)**

Characteristic		Symbol	Test Condition	Min	Typ.	Max	Unit
LED	Forward voltage	V <sub>F</sub>	I <sub>F</sub> = 10 mA	1.0	1.15	1.3	V
	Reverse current	I <sub>R</sub>	V <sub>R</sub> = 5 V	—	—	10	μA
	Capacitance	C <sub>T</sub>	V = 0, f = 1 MHz	—	30	—	pF
Detector	Collector-emitter breakdown voltage	V <sub>(BR) CEO</sub>	I <sub>C</sub> = 0.5 mA	55	—	—	V
	Emitter-collector breakdown voltage	V <sub>(BR) ECO</sub>	I <sub>E</sub> = 0.1 mA	7	—	—	V
	Collector dark current	I <sub>CEO</sub>	V <sub>CE</sub> = 24 V	—	10	100	nA
			V <sub>CE</sub> = 24 V, Ta = 85°C	—	2	50	μA
	Capacitance (collector to emitter)	C <sub>CE</sub>	V = 0, f = 1 MHz	—	10	—	pF

**Coupled Electrical Characteristics (Ta = 25°C)**

Characteristic	Symbol	Test Condition	Min	Typ.	Max	Unit
Current transfer ratio	I <sub>C</sub> / I <sub>F</sub>	I <sub>F</sub> = 5 mA, V <sub>CE</sub> = 5 V Rank GB	50	—	600	%
			100	—	600	
Saturated CTR	I <sub>C</sub> / I <sub>F</sub> (sat)	I <sub>F</sub> = 1 mA, V <sub>CE</sub> = 0.4 V Rank GB	—	60	—	%
			30	—	—	
Collector-emitter saturation voltage	V <sub>CE</sub> (sat)	I <sub>C</sub> = 2.4 mA, I <sub>F</sub> = 8 mA	—	—	0.4	V
		I <sub>C</sub> = 0.2 mA, I <sub>F</sub> = 1 mA Rank GB	—	0.2	—	
			—	—	0.4	

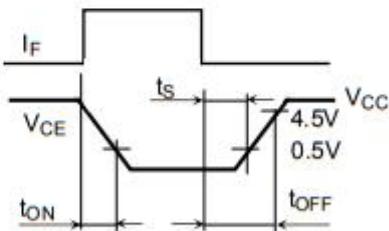
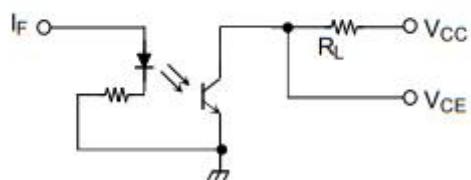
**Isolation Characteristics (Ta = 25°C)**

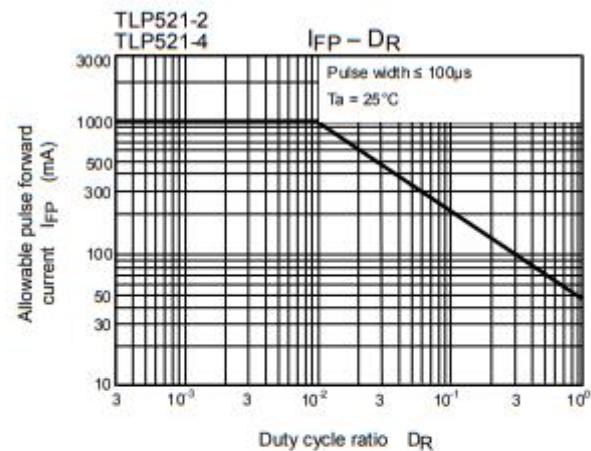
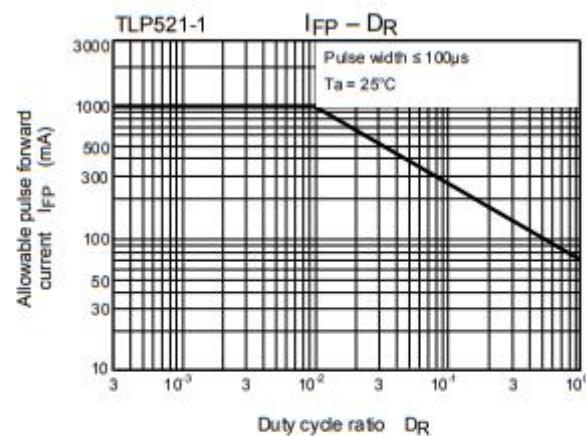
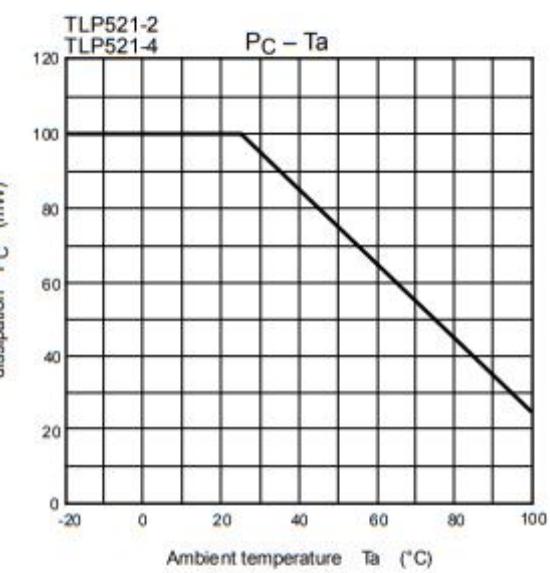
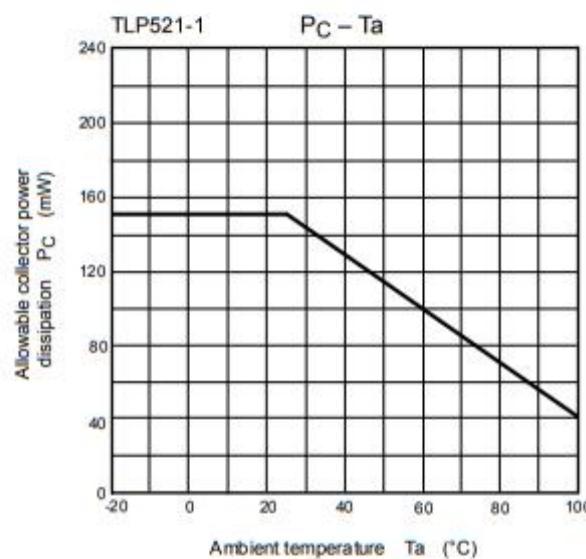
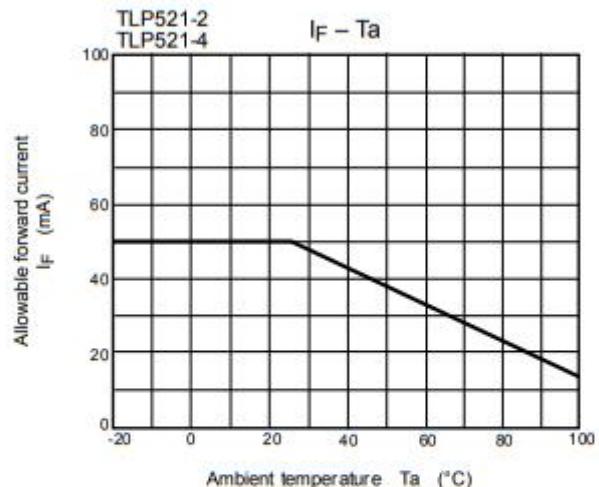
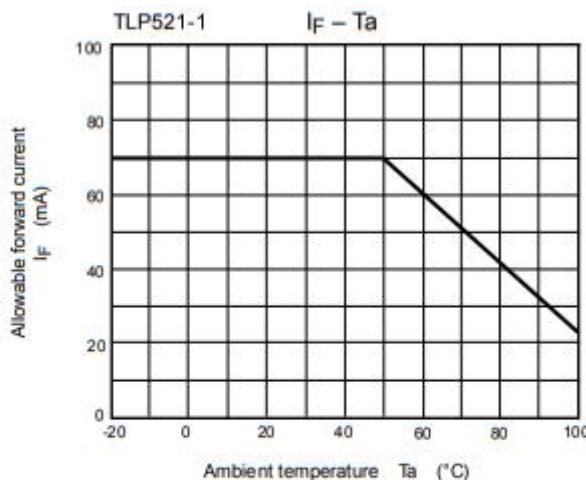
Characteristic	Symbol	Test Condition	Min	Typ.	Max	Unit
Capacitance (input to output)	C <sub>S</sub>	V <sub>S</sub> = 0, f = 1 MHz	—	0.8	—	pF
Isolation resistance	R <sub>S</sub>	V <sub>S</sub> = 500 V, R.H.≤60%	—	10 <sup>11</sup>	—	Ω
Isolation voltage	BVs	AC, 1 minute	2500	—	—	Vrms
		AC, 1 second, in oil	—	5000	—	
		DC, 1 minute, in oil	—	5000	—	Vdc

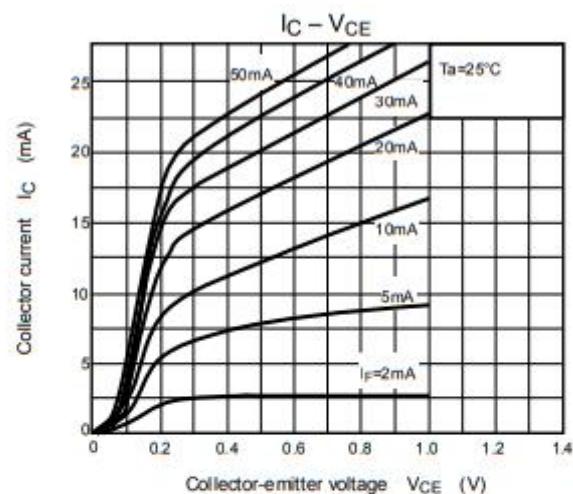
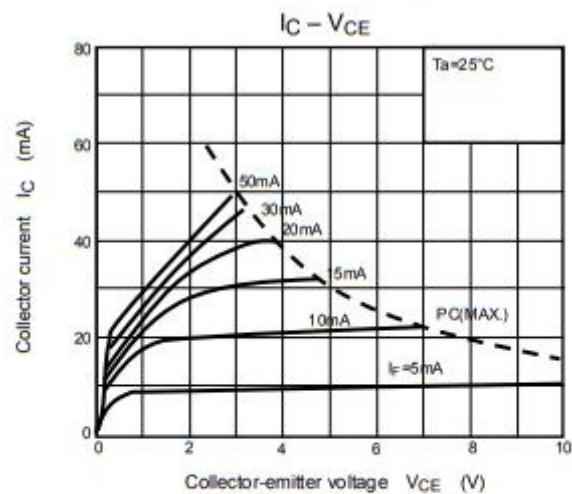
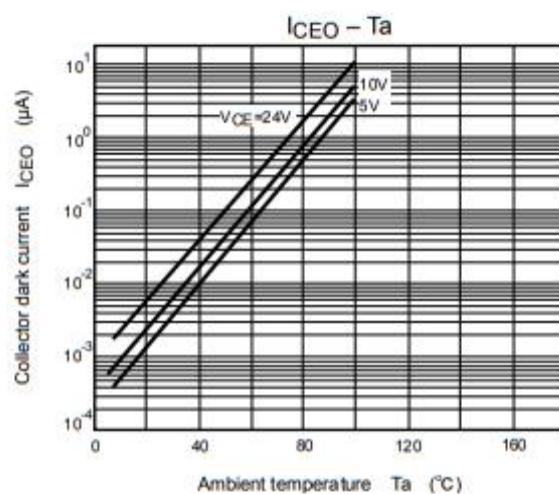
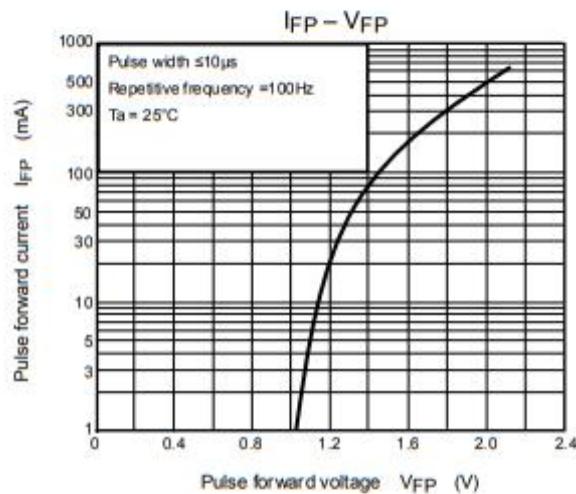
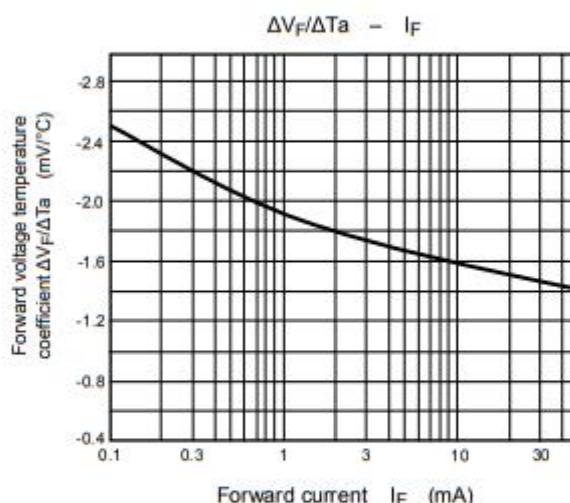
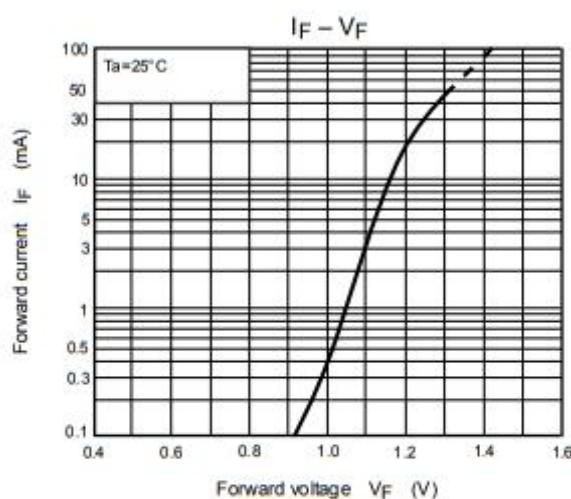
Switching Characteristics ( $T_a = 25^\circ\text{C}$ )

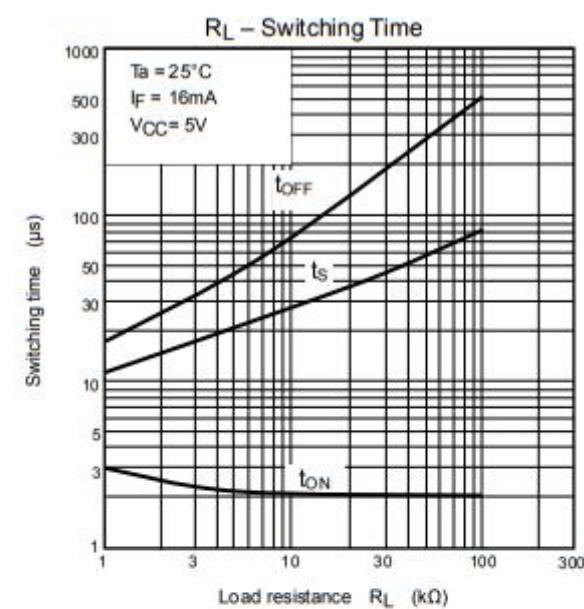
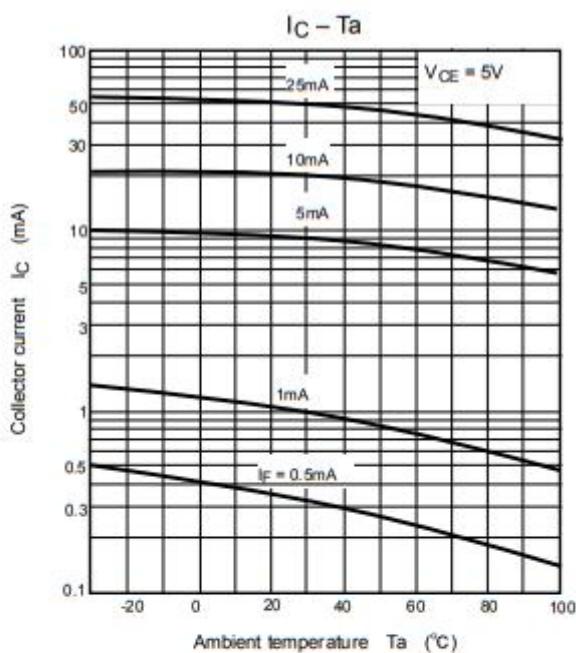
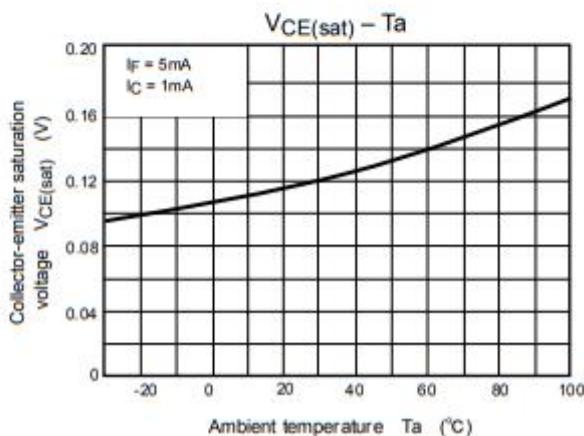
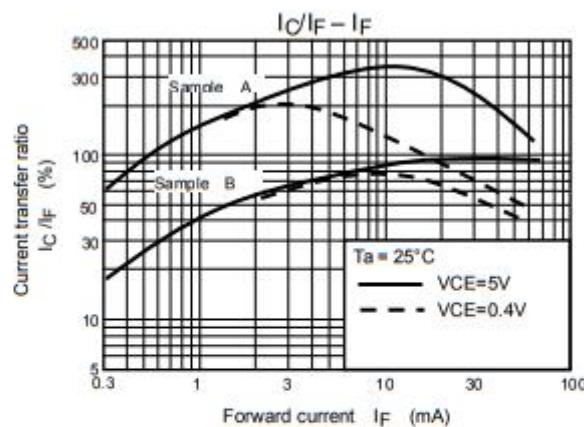
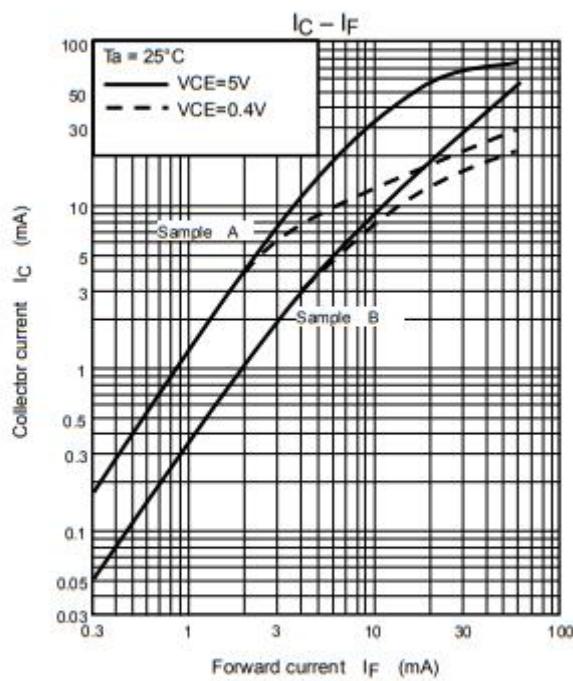
Characteristic	Symbol	Test Condition	Min	Typ.	Max	Unit
Rise time	$t_r$	$V_{CC} = 10\text{ V}$ $I_C = 2\text{ mA}$ $R_L = 100\Omega$	—	2	—	$\mu\text{s}$
Fall time	$t_f$		—	3	—	
Turn-on time	$t_{ON}$		—	3	—	
Turn-off time	$t_{OFF}$		—	3	—	
Turn-on time	$t_{ON}$	$R_L = 1.9\text{ k}\Omega$ (Fig.1) $V_{CC} = 5\text{ V}$ , $I_F = 16\text{ mA}$	—	2	—	$\mu\text{s}$
Storage time	$t_s$		—	15	—	
Turn-off time	$t_{OFF}$		—	25	—	

Fig.1 : SWITCHING TIME TEST CIRCUIT









**RESTRICTIONS ON PRODUCT USE**

20070701-EN

- The information contained herein is subject to change without notice.
- TOSHIBA is continually working to improve the quality and reliability of its products. Nevertheless, semiconductor devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to comply with the standards of safety in making a safe design for the entire system, and to avoid situations in which a malfunction or failure of such TOSHIBA products could cause loss of human life, bodily injury or damage to property.  
In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent TOSHIBA products specifications. Also, please keep in mind the precautions and conditions set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA Semiconductor Reliability Handbook" etc.
- The TOSHIBA products listed in this document are intended for usage in general electronics applications (computer, personal equipment, office equipment, measuring equipment, industrial robotics, domestic appliances, etc.). These TOSHIBA products are neither intended nor warranted for usage in equipment that requires extraordinarily high quality and/or reliability or a malfunction or failure of which may cause loss of human life or bodily injury ("Unintended Usage"). Unintended Usage include atomic energy control instruments, airplane or spaceship instruments, transportation instruments, traffic signal instruments, combustion control instruments, medical instruments, all types of safety devices, etc.. Unintended Usage of TOSHIBA products listed in his document shall be made at the customer's own risk.
- The products described in this document shall not be used or embedded to any downstream products of which manufacture, use and/or sale are prohibited under any applicable laws and regulations.
- The information contained herein is presented only as a guide for the applications of our products. No responsibility is assumed by TOSHIBA for any infringements of patents or other rights of the third parties which may result from its use. No license is granted by implication or otherwise under any patents or other rights of TOSHIBA or the third parties.
- GaAs(Gallium Arsenide) is used in this product. The dust or vapor is harmful to the human body. Do not break, cut, crush or dissolve chemically.
- Please contact your sales representative for product-by-product details in this document regarding RoHS compatibility. Please use these products in this document in compliance with all applicable laws and regulations that regulate the inclusion or use of controlled substances. Toshiba assumes no liability for damage or losses occurring as a result of noncompliance with applicable laws and regulations.